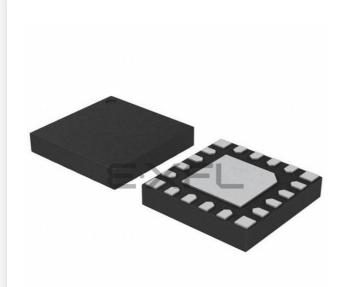
E·XFL



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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

Product Status	Active
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	25MHz
Connectivity	I ² C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	16
Program Memory Size	4KB (4K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	512 x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 15x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	20-UFQFN Exposed Pad
Supplier Device Package	20-QFN (3x3)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8bb10f4g-a-qfn20

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

3.2 Power

All internal circuitry draws power from the VDD supply pin. External I/O pins are powered from the VIO supply voltage (or VDD on devices without a separate VIO connection), while most of the internal circuitry is supplied by an on-chip LDO regulator. Control over the device power can be achieved by enabling/disabling individual peripherals as needed. Each analog peripheral can be disabled when not in use and placed in low power mode. Digital peripherals, such as timers and serial buses, have their clocks gated off and draw little power when they are not in use.

Table 3.1. Power Modes

Power Mode	Details	Mode Entry	Wake-Up Sources
Normal	Core and all peripherals clocked and fully operational	—	—
Idle	 Core halted All peripherals clocked and fully operational Code resumes execution on wake event 	Set IDLE bit in PCON0	Any interrupt
Stop	 All internal power nets shut down Pins retain state Exit on any reset source 	1. Clear STOPCF bit in REG0CN 2. Set STOP bit in PCON0	Any reset source
Shutdown	 All internal power nets shut down Pins retain state Exit on pin or power-on reset 	1. Set STOPCF bit in REG0CN 2. Set STOP bit in PCON0	RSTb pin resetPower-on reset

3.3 I/O

Digital and analog resources are externally available on the device's multi-purpose I/O pins. Port pins P0.0-P1.7 can be defined as general-purpose I/O (GPIO), assigned to one of the internal digital resources through the crossbar or dedicated channels, or assigned to an analog function. Port pins P2.0 and P2.1 can be used as GPIO. Additionally, the C2 Interface Data signal (C2D) is shared with P2.0.

- Up to 18 multi-functions I/O pins, supporting digital and analog functions.
- Flexible priority crossbar decoder for digital peripheral assignment.
- Two drive strength settings for each port.
- Two direct-pin interrupt sources with dedicated interrupt vectors (INT0 and INT1).
- · Up to 16 direct-pin interrupt sources with shared interrupt vector (Port Match).

3.4 Clocking

The CPU core and peripheral subsystem may be clocked by both internal and external oscillator resources. By default, the system clock comes up running from the 24.5 MHz oscillator divided by 8.

- Provides clock to core and peripherals.
- 24.5 MHz internal oscillator (HFOSC0), accurate to ±2% over supply and temperature corners.
- 80 kHz low-frequency oscillator (LFOSC0).
- External CMOS clock input (EXTCLK).
- Clock divider with eight settings for flexible clock scaling: Divide the selected clock source by 1, 2, 4, 8, 16, 32, 64, or 128.

3.6 Communications and Other Digital Peripherals

Universal Asynchronous Receiver/Transmitter (UART0)

UART0 is an asynchronous, full duplex serial port offering modes 1 and 3 of the standard 8051 UART. Enhanced baud rate support allows a wide range of clock sources to generate standard baud rates. Received data buffering allows UART0 to start reception of a second incoming data byte before software has finished reading the previous data byte.

The UART module provides the following features:

- · Asynchronous transmissions and receptions.
- Baud rates up to SYSCLK/2 (transmit) or SYSCLK/8 (receive).
- 8- or 9-bit data.
- Automatic start and stop generation.
- Single-byte FIFO on transmit and receive.

Serial Peripheral Interface (SPI0)

The serial peripheral interface (SPI) module provides access to a flexible, full-duplex synchronous serial bus. The SPI can operate as a master or slave device in both 3-wire or 4-wire modes, and supports multiple masters and slaves on a single SPI bus. The slave-select (NSS) signal can be configured as an input to select the SPI in slave mode, or to disable master mode operation in a multi-master environment, avoiding contention on the SPI bus when more than one master attempts simultaneous data transfers. NSS can also be configured as a firmware-controlled chip-select output in master mode, or disable to reduce the number of pins required. Additional general purpose port I/O pins can be used to select multiple slave devices in master mode.

The SPI module includes the following features:

- · Supports 3- or 4-wire operation in master or slave modes.
- Supports external clock frequencies up to SYSCLK / 2 in master mode and SYSCLK / 10 in slave mode.
- · Support for four clock phase and polarity options.
- 8-bit dedicated clock clock rate generator.
- Support for multiple masters on the same data lines.

System Management Bus / I2C (SMB0)

The SMBus I/O interface is a two-wire, bi-directional serial bus. The SMBus is compliant with the System Management Bus Specification, version 1.1, and compatible with the I^2 C serial bus.

The SMBus module includes the following features:

- Standard (up to 100 kbps) and Fast (400 kbps) transfer speeds.
- Support for master, slave, and multi-master modes.
- Hardware synchronization and arbitration for multi-master mode.
- Clock low extending (clock stretching) to interface with faster masters.
- Hardware support for 7-bit slave and general call address recognition.
- Firmware support for 10-bit slave address decoding.
- · Ability to inhibit all slave states.
- Programmable data setup/hold times.

16-bit CRC (CRC0)

The cyclic redundancy check (CRC) module performs a CRC using a 16-bit polynomial. CRC0 accepts a stream of 8-bit data and posts the 16-bit result to an internal register. In addition to using the CRC block for data manipulation, hardware can automatically CRC the flash contents of the device.

The CRC module is designed to provide hardware calculations for flash memory verification and communications protocols. The CRC module supports the standard CCITT-16 16-bit polynomial (0x1021), and includes the following features:

- Support for CCITT-16 polynomial
- Byte-level bit reversal
- Automatic CRC of flash contents on one or more 256-byte blocks
- Initial seed selection of 0x0000 or 0xFFFF

3.7 Analog

12-Bit Analog-to-Digital Converter (ADC0)

The ADC is a successive-approximation-register (SAR) ADC with 12-, 10-, and 8-bit modes, integrated track-and hold and a programmable window detector. The ADC is fully configurable under software control via several registers. The ADC may be configured to measure different signals using the analog multiplexer. The voltage reference for the ADC is selectable between internal and external reference sources.

- Up to 16 external inputs.
- Single-ended 12-bit and 10-bit modes.
- Supports an output update rate of 200 ksps samples per second in 12-bit mode or 800 ksps samples per second in 10-bit mode.
- Operation in low power modes at lower conversion speeds.
- Asynchronous hardware conversion trigger, selectable between software, external I/O and internal timer sources.
- · Output data window comparator allows automatic range checking.
- Support for burst mode, which produces one set of accumulated data per conversion-start trigger with programmable power-on settling and tracking time.
- · Conversion complete and window compare interrupts supported.
- Flexible output data formatting.
- Includes an internal fast-settling reference with two levels (1.65 V and 2.4 V) and support for external reference and signal ground.
- Integrated temperature sensor.

Low Current Comparators (CMP0, CMP1)

Analog comparators are used to compare the voltage of two analog inputs, with a digital output indicating which input voltage is higher. External input connections to device I/O pins and internal connections are available through separate multiplexers on the positive and negative inputs. Hysteresis, response time, and current consumption may be programmed to suit the specific needs of the application.

The comparator module includes the following features:

- Up to 8 external positive inputs.
- Up to 8 external negative inputs.
- · Additional input options:
 - Internal connection to LDO output.
 - · Direct connection to GND.
- · Synchronous and asynchronous outputs can be routed to pins via crossbar.
- Programmable hysteresis between 0 and ±20 mV
- Programmable response time.
- Interrupts generated on rising, falling, or both edges.

Device Package	Pin for Bootload Mode Entry
QSOP24	P2.0 / C2D
QFN20	P2.0 / C2D
SOIC16	P2.0 / C2D

Table 3.3. Summary of Pins for Bootload Mode Entry

4. Electrical Specifications

4.1 Electrical Characteristics

All electrical parameters in all tables are specified under the conditions listed in Table 4.1 Recommended Operating Conditions on page 12, unless stated otherwise.

4.1.1 Recommended Operating Conditions

Table 4.1. Recommended Operating Conditions

Parameter	Symbol	Test Condition	Min	Тур	Мах	Unit
Operating Supply Voltage on VDD	V _{DD}		2.2	—	3.6	V
System Clock Frequency	f _{SYSCLK}		0	_	25	MHz
Operating Ambient Temperature	T _A	G-grade devices	-40	_	85	°C
		I-grade or A-grade devices	-40	_	125	°C
Note:						

1. All voltages with respect to GND

2. GPIO levels are undefined whenever VDD is less than 1 V.

4.1.4 Flash Memory

Parameter	Symbol	Test Condition	Min	Тур	Мах	Units
Write Time ^{1,2}	t _{WRITE}	One Byte,	19	20	21	μs
		F _{SYSCLK} = 24.5 MHz				
Erase Time ^{1,2}	t _{ERASE}	One Page,	5.2	5.35	5.5	ms
		F _{SYSCLK} = 24.5 MHz				
V _{DD} Voltage During Programming ³	V _{PROG}		2.2	—	3.6	V
Endurance (Write/Erase Cycles)	N _{WE}		20k	100k	—	Cycles
CRC Calculation Time	t _{CRC}	One 256-Byte Block	_	11	_	μs
		SYSCLK = 24.5 MHz				

Table 4.4. Flash Memory

Note:

1. Does not include sequencing time before and after the write/erase operation, which may be multiple SYSCLK cycles.

2. The internal High-Frequency Oscillator has a programmable output frequency using the HFO0CAL register, which is factory programmed to 24.5 MHz. If user firmware adjusts the oscillator speed, it must be between 22 and 25 MHz during any flash write or erase operation. It is recommended to write the HFO0CAL register back to its reset value when writing or erasing flash.

3. Flash can be safely programmed at any voltage above the supply monitor threshold (V_{VDDM}).

4. Data Retention Information is published in the Quarterly Quality and Reliability Report.

4.1.5 Internal Oscillators

Table 4.5. Internal Oscillators

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit	
High Frequency Oscillator 0 (24.5 MHz)							
Oscillator Frequency	f _{HFOSC0}	Full Temperature and Supply Range	24	24.5	25	MHz	
Power Supply Sensitivity	PSS _{HFOS} C0	T _A = 25 °C	—	0.5		%/V	
Temperature Sensitivity	TS _{HFOSC0}	V _{DD} = 3.0 V	_	40	_	ppm/°C	
Low Frequency Oscillator (80 k	Hz)						
Oscillator Frequency	f _{LFOSC}	Full Temperature and Supply Range	75	80	85	kHz	
Power Supply Sensitivity	PSS _{LFOSC}	T _A = 25 °C	_	0.05	_	%/V	
Temperature Sensitivity	TS _{LFOSC}	V _{DD} = 3.0 V	_	65	_	ppm/°C	

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Negative Hysteresis	HYS _{CP-}	CPHYN = 00	_	-1.5	_	mV
Mode 3 (CPMD = 11)		CPHYN = 01	_	-4	_	mV
		CPHYN = 10	—	-8	_	mV
		CPHYN = 11	_	–16	_	mV
Input Range (CP+ or CP-)	V _{IN}		-0.25	_	V _{DD} +0.25	V
Input Pin Capacitance	C _{CP}		—	7.5	—	pF
Common-Mode Rejection Ratio	CMRR _{CP}		—	70	—	dB
Power Supply Rejection Ratio	PSRR _{CP}		—	72	_	dB
Input Offset Voltage	V _{OFF}	T _A = 25 °C	-10	0	10	mV
Input Offset Tempco	TC _{OFF}		_	3.5	_	µV/°C

4.1.13 SMBus

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Standard Mode (100 kHz Class)						
I2C Operating Frequency	f _{I2C}		0	_	70 ²	kHz
SMBus Operating Frequency	f _{SMB}		40 ¹	—	70 ²	kHz
Bus Free Time Between STOP and START Conditions	t _{BUF}		9.4	_	_	μs
Hold Time After (Repeated) START Condition	t _{HD:STA}		4.7	_	_	μs
Repeated START Condition Setup Time	t _{SU:STA}		9.4	_	_	μs
STOP Condition Setup Time	t _{SU:STO}		9.4	—	—	μs
Data Hold Time	t _{HD:DAT}		489 ³	—	_	ns
Data Setup Time	t _{SU:DAT}		448 ³	—	—	ns
Detect Clock Low Timeout	t _{TIMEOUT}		25	—	—	ms
Clock Low Period	t _{LOW}		4.7	_	—	μs
Clock High Period	t _{HIGH}		9.4	—	50 ⁴	μs
Fast Mode (400 kHz Class)						
I2C Operating Frequency	f _{I2C}		0	-	255 ²	kHz
SMBus Operating Frequency	f _{SMB}		40 ¹	—	255 ²	kHz
Bus Free Time Between STOP and START Conditions	t _{BUF}		2.6	—	_	μs
Hold Time After (Repeated) START Condition	t _{HD:STA}		1.3	_	_	μs
Repeated START Condition Setup Time	t _{SU:STA}		2.6	_	_	μs
STOP Condition Setup Time	t _{SU:STO}		2.6	_		μs
Data Hold Time	t _{HD:DAT}		489 ³	—	—	ns
Data Setup Time	t _{SU:DAT}		448 ³	—	—	ns
Detect Clock Low Timeout	t _{TIMEOUT}		25	-	—	ms
Clock Low Period	t _{LOW}		1.3	—	—	μs
Clock High Period	t _{HIGH}		2.6	_	50 ⁴	μs

Table 4.13. SMBus Peripheral Timing Performance (Master Mode)

4.2 Thermal Conditions

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit		
Thermal Resistance (Junction to	θ _{JA}	SOIC-16 Packages	_	70	_	°C/W		
Ambient)		QFN-20 Packages	_	60	_	°C/W		
		QSOP-24 Packages	—	65	_	°C/W		
Thermal Resistance (Junction to Case)	θ _{JC}	QFN-20 Packages	-	28.86	_	°C/W		
Note: 1. Thermal resistance assumes a multi-layer PCB with any exposed pad soldered to a PCB pad.								

Table 4.15. Thermal Conditions

4.3 Absolute Maximum Ratings

Stresses above those listed in Table 4.16 Absolute Maximum Ratings on page 26 may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at http://www.silabs.com/support/quality/pages/default.aspx.

Table 4.16. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T _{BIAS}		-55	125	°C
Storage Temperature	T _{STG}		-65	150	°C
Voltage on VDD	V _{DD}		GND-0.3	4.2	V
Voltage on I/O pins or RST	V _{IN}	V _{DD} ≥ 3.3 V	GND-0.3	5.8	V
		V < 3.3 V	GND-0.3	V _{DD} +2.5	V
Total Current Sunk into Supply Pin	I _{VDD}		-	200	mA DD
Total Current Sourced out of Ground Pin	I _{GND}		200	_	mA
Current Sourced or Sunk by Any I/O Pin or RSTb	I _{IO}		-100	100	mA
Operating Junction Temperature	TJ	T _A = -40 °C to 85 °C	-40	105	°C
		T_A = -40 °C to 125 °C (I-grade or A- grade parts only)	-40	130	°C
Exposure to maximum rating condition	s for extende	ed periods may affect device reliability.	1	1	

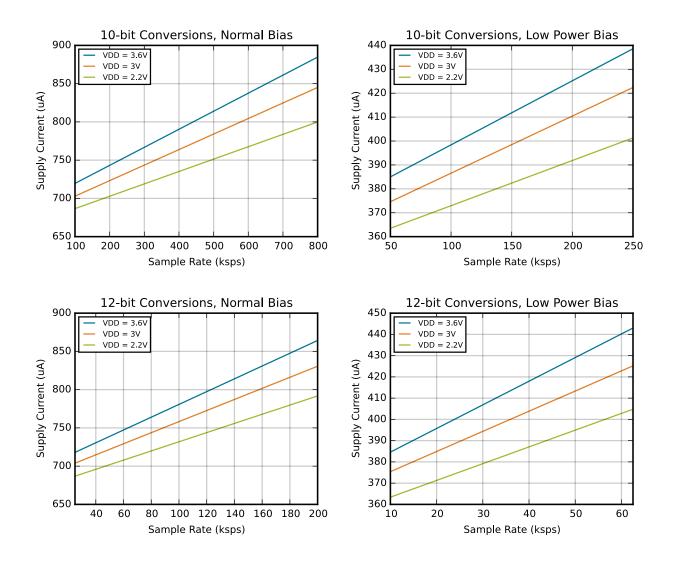


Figure 4.5. Typical ADC0 Supply Current in Normal (always-on) Mode

5. Typical Connection Diagrams

5.1 Power

Figure 5.1 Power Connection Diagram on page 31 shows a typical connection diagram for the power pins of the EFM8BB1 devices.

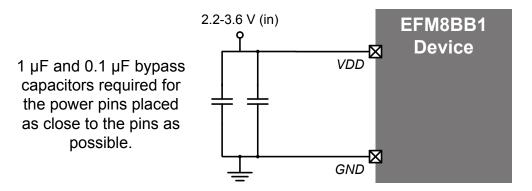


Figure 5.1. Power Connection Diagram

5.2 Debug

The diagram below shows a typical connection diagram for the debug connections pins. The pin sharing resistors are only required if the functionality on the C2D (a GPIO pin) and the C2CK (RSTb) is routed to external circuitry. For example, if the RSTb pin is connected to an external switch with debouncing filter or if the GPIO sharing with the C2D pin is connected to an external circuit, the pin sharing resistors and connections to the debug adapter must be placed on the hardware. Otherwise, these components and connections can be omitted.

For more information on debug connections, see the example schematics and information available in application note, "AN127: Pin Sharing Techniques for the C2 Interface." Application notes can be found on the Silicon Labs website (http://www.silabs.com/8bit-appnotes) or in Simplicity Studio.

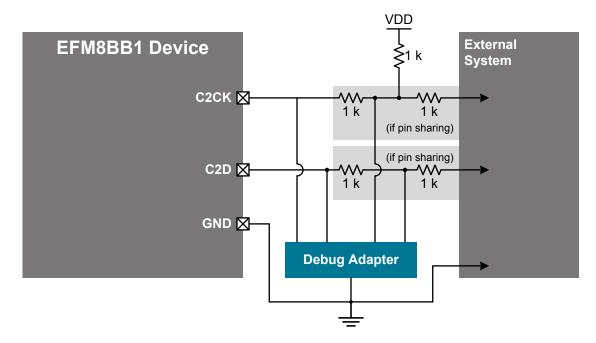


Figure 5.2. Debug Connection Diagram

Pin	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
Number				Tunctions	
3	GND	Ground			
4	VDD	Supply Power Input			
5	RSTb /	Active-low Reset /			
	C2CK	C2 Debug Clock			
6	P2.0 /	Multifunction I/O /			
	C2D	C2 Debug Data			
7	P1.6	Multifunction I/O	Yes	P1MAT.6	ADC0.14
					CMP1P.6
					CMP1N.6
8	P1.5	Multifunction I/O	Yes	P1MAT.5	ADC0.13
					CMP1P.5
					CMP1N.5
9	P1.4	Multifunction I/O	Yes	P1MAT.4	ADC0.12
					CMP1P.4
					CMP1N.4
10	P1.3	Multifunction I/O	Yes	P1MAT.3	ADC0.11
					CMP1P.3
					CMP1N.3
11	P1.2	Multifunction I/O	Yes	P1MAT.2	ADC0.10
					CMP1P.2
					CMP1N.2
12	GND	Ground			
13	P1.1	Multifunction I/O	Yes	P1MAT.1	ADC0.9
					CMP1P.1
					CMP1N.1
14	P1.0	Multifunction I/O	Yes	P1MAT.0	ADC0.8
					CMP1P.0
					CMP1N.0
15	P0.7	Multifunction I/O	Yes	P0MAT.7	ADC0.7
				INT0.7	CMP0P.7
				INT1.7	CMP0N.7
16	P0.6	Multifunction I/O	Yes	P0MAT.6	ADC0.6
				CNVSTR	CMP0P.6
				INT0.6	CMP0N.6
				INT1.6	

Pin	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
Number					
4	GND	Ground			
5	VDD	Supply Power Input			
6	RSTb /	Active-low Reset /			
	C2CK	C2 Debug Clock			
7	P2.0 /	Multifunction I/O /			
	C2D	C2 Debug Data			
8	P1.3	Multifunction I/O	Yes	P1MAT.3	ADC0.11
					CMP1P.5
					CMP1N.5
9	P1.2	Multifunction I/O	Yes	P1MAT.2	ADC0.10
					CMP1P.4
					CMP1N.4
10	P1.1	Multifunction I/O	Yes	P1MAT.1	ADC0.9
					CMP1P.3
					CMP1N.3
11	P1.0	Multifunction I/O	Yes	P1MAT.0	ADC0.8
					CMP1P.2
					CMP1N.2
12	P0.7	Multifunction I/O	Yes	P0MAT.7	ADC0.7
				INT0.7	CMP1P.1
				INT1.7	CMP1N.1
13	P0.6	Multifunction I/O	Yes	P0MAT.6	ADC0.6
				CNVSTR	CMP1P.0
				INT0.6	CMP1N.0
				INT1.6	
14	P0.5	Multifunction I/O	Yes	P0MAT.5	ADC0.5
				INT0.5	CMP0P.5
				INT1.5	CMP0N.5
15	P0.4	Multifunction I/O	Yes	P0MAT.4	ADC0.4
				INT0.4	CMP0P.4
				INT1.4	CMP0N.4
16	P0.3	Multifunction I/O	Yes	P0MAT.3	ADC0.3
				EXTCLK	CMP0P.3
				INT0.3	CMP0N.3
				INT1.3	

7. QSOP24 Package Specifications

7.1 QSOP24 Package Dimensions

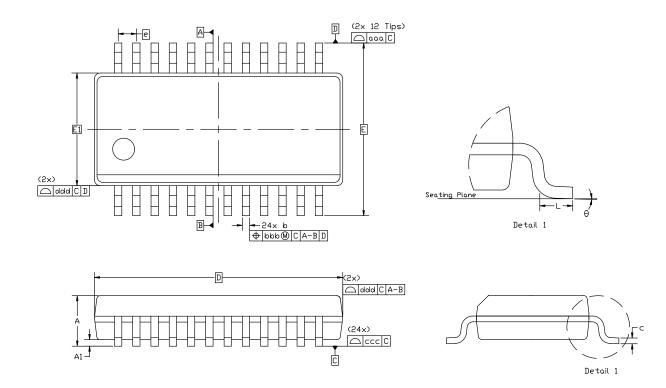


Figure 7.1. QSOP24 Package Drawing

Table 7.1. QSOP24 Package Dimensions

Dimension	Min	Тур	Мах
A	_	—	1.75
A1	0.10	—	0.25
b	0.20	—	0.30
С	0.10	_	0.25
D	8.65 BSC		
E	6.00 BSC		
E1	3.90 BSC		
e	0.635 BSC		
L	0.40	—	1.27
theta	0°	—	8°

Min	Тур	Мах
	0.20	
	0.18	
	0.10	
	0.10	
	Min	0.20 0.18 0.10

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.

2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.

3. This drawing conforms to JEDEC outline MO-137, variation AE.

4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

7.2 QSOP24 PCB Land Pattern

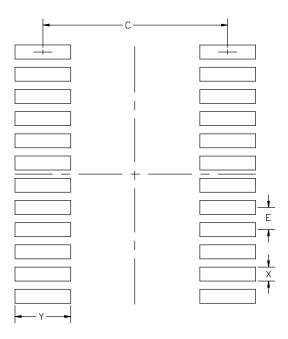


Figure 7.2. QSOP24 PCB Land Pattern Drawing

Table 7.2.	QSOP24 PCB Land Pattern I	Dimensions
------------	---------------------------	------------

Dimension	Min	Мах	
С	5.20	5.30	
E	0.635 BSC		
X	0.30	0.40	
Y	1.50	1.60	

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.

2. This land pattern design is based on the IPC-7351 guidelines.

3. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.

4. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.

5. The stencil thickness should be 0.125 mm (5 mils).

6. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads.

7. A No-Clean, Type-3 solder paste is recommended.

8. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.



Figure 7.3. QSOP24 Package Marking

The package marking consists of:

- PPPPPPP The part number designation.
- TTTTTT A trace or manufacturing code.
- YY The last 2 digits of the assembly year.
- WW The 2-digit workweek when the device was assembled.
- # The device revision (A, B, etc.).

8. QFN20 Package Specifications

8.1 QFN20 Package Dimensions

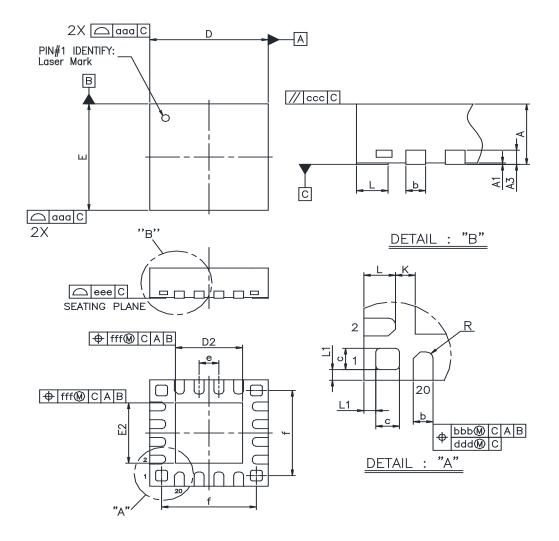


Figure 8.1. QFN20 Package Drawing

Table 8.1.	QFN20	Package	Dimensions
------------	-------	---------	------------

Dimension	Min	Тур	Мах
A	0.70	0.75	0.80
A1	0.00	0.02	0.05
A3	0.20 REF		
b	0.18	0.25	0.30
С	0.25	0.30	0.35
D	3.00 BSC		
D2	1.6	1.70	1.80
е	0.50 BSC		

Dimension	Min	Тур	Max
E	3.00 BSC		
E2	1.60	1.70	1.80
f	2.50 BSC		
L	0.30	0.40	0.50
К	0.25 REF		
R	0.09	0.125	0.15
aaa	0.15		
bbb	0.10		
ссс	0.10		
ddd	0.05		
eee	0.08		
fff	0.10		

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.

2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.

3. The drawing complies with JEDEC MO-220.

4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

9.2 SOIC16 PCB Land Pattern

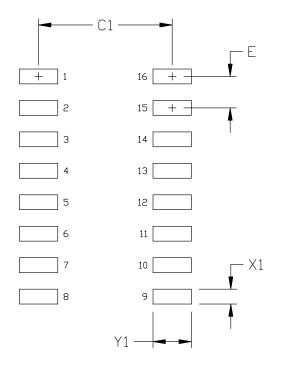


Figure 9.2. SOIC16 PCB Land Pattern Drawing

Table 9.2.	SOIC16 PCB	Land Pattern	Dimensions
------------	------------	--------------	------------

Dimension	Feature	(mm)
C1	Pad Column Spacing	5.40
E	Pad Row Pitch	1.27
X1	Pad Width	0.60
Y1	Pad Length	1.55

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.

2. This Land Pattern Design is based on IPC-7351 pattern SOIC127P600X165-16N for Density Level B (Median Land Protrusion).

3. All feature sizes shown are at Maximum Material Condition (MMC) and a card fabrication tolerance of 0.05 mm is assumed.